Special Issue

Application of X-ray Computed Tomography

Message from the Guest Editors

We are inviting submissions to this Special Issue on the "Application of X-ray Computed Tomography". X-ray computed tomography is a widespread analysis technique. The spectrum of its applications ranges from medicine to metallurgy, microelectronics, geoscience, material science, engineering, 3D printing, etc. Its very high spatial and temporal resolution, together with its non-invasive character, makes X-ray computed tomography the best option of analysis in many cases. In this Special Issue, we invite authors to present their latest cutting-edge research in the field.

Guest Editors

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Deadline for manuscript submissions

closed (20 August 2023)

About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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